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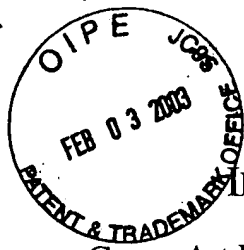
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PATENT
Docket No.: LMPY-12910

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE
Group Art Unit: 2881 Examiner:

Serial No.: 09/903,425 Filed: July 10, 2001

In re Application of: Hans-Stephan Albrecht, et al.

For: PRECISE MONITOR ETALON CALIBRATION TECHNIQUE

Certificate of Mailing

I hereby certify that this correspondence is being deposited with the United States Postal Service with sufficient postage as First Class Mail, in an envelope addressed to Director of Patents, Washington, D.C. 20231 on 10-9-02, Signed Gerry Ubau
Gerry Ubau

INFORMATION DISCLOSURE STATEMENT

Director of Patents
Washington, D.C. 20231

Dear Sir:

Each item of information listed in the attached FORM PTO-1449, for which a copy of each is attached, may be material to the examination of the above-identified application and is, therefore, submitted in compliance with the duty of disclosure defined in 37 CFR §§1.56, 1.97 and 1.98. The Examiner is requested to make these items of official record in this application.

This Information Disclosure Statement under 37 CFR §§1.56, 1.97 and 1.98 is not to be construed as a representation that a search has been made, that additional information material to the examination of this application does not exist, or that any one or more of these items constitutes prior art.

I



This statement is filed pursuant to:

37 C.F.R. §1.97(b).

This information disclosure statement is filed either (1) within three months of the filing date of the national applications; (2) within three months of the date of entry of the national stage as set forth in 37 C.F.R. §1.491 in an international application; or (3) before the mailing date of a first office action on the merits, whichever event occurs last.

Accordingly, this information disclosure statement requires no fee and no certification.

() 37 C.F.R. §1.97(c).

This information disclosure statement is filed after the period specified in 37 C.F.R. §1.97(b), but before the mailing date of either (1) a final action under 37 C.F.R. §1.113 or (2) a notice of allowance under 37 C.F.R. §1.311.

Accordingly, this information disclosure statement requires either the fee specified in 37 C.F.R. §1.17 (p) or a certification according to 37 C.F.R. §1.97(e).

() 37 C.F.R. §1.97(d).

This information disclosure statement is filed after the period specified in 37 C.F.R. §1.97(c).

Accordingly, this information disclosure statement requires the fee specified in 37 C.F.R. §1.17(p), \$180.00, for submission of an information disclosure statement under 37 C.F.R. §1.97(d), and a statement according to 37 C.F.R. §1.97(e).

37 C.F.R. §1.97(e).

() (1) Each item of information contained in the information disclosure statement was cited in a communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of the statement.

() (2) No item of information contained in the information disclosure statement was cited in a communication from a foreign patent office in a counterpart foreign application, or, to my knowledge after making reasonable inquiry, was known to any individual designated in 37 C.F.R. §1.56(c), more than three months prior to the filing of the statement.

Accordingly, this information disclosure statement requires the fee specified in 37 C.F.R. §1.17(p), \$180.00, for submission of an information disclosure statement under 37 C.F.R. §1.97(e).

If this statement crosses in the mail with an office action, or is otherwise not in the indicated category of 37 C.F.R. §1.97, it is respectfully requested that this statement be treated in the next appropriate category and made of record. To the extent required, please treat this paper as a conditional petition for acceptance of the information disclosure statement.

II

- (X) No fee is due.
- () The fee specified in 37 C.F.R. §1.17(p) for submission of an information disclosure statement under 37 C.F.R. §1.97(c), 37 C.F.R § 1.97(d), or 37 C.F.R. §1.97(e) is enclosed, \$180.00.

In the event any fee is required for filing the above-noted document, including any fees required under 37 CFR 1.136 for any necessary Extension of Time to make the filing attached document timely, the Assistant Commissioner is hereby authorized to charge the fee to our Deposit Account No. 50-0612. A duplicate of this page is enclosed.

Respectfully submitted,
SIERRA PATENT GROUP, LTD.

Dated: 10-6-02



Andrew V. Smith
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II

(X) No fee is due.

() The fee specified in 37 C.F.R. §1.17(p) for submission of an information disclosure statement under 37 C.F.R. §1.97(c), 37 C.F.R. § 1.97(d), or 37 C.F.R. §1.97(e) is enclosed, \$180.00.

In the event any fee is required for filing the above-noted document, including any fees required under 37 CFR 1.136 for any necessary Extension of Time to make the filing attached document timely, the Assistant Commissioner is hereby authorized to charge the fee to our Deposit Account No. 50-0612. A duplicate of this page is enclosed.

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Form PTO 1449
(Rev. 2-32)U.S. Department of Commerce
Patent and Trademark OfficeAtty. Docket No.
LMPY-12910Serial No.
09/903,425

Information Disclosure Statement by Applicant

Applicant:
Hans-Stephan Albrecht, et al.

(Use several sheets if necessary)

Filed: July 10, 2001 Group: 2881

U.S. Patent Documents

Init.	Document No.	Date	Name	Class	Subclass	Filing Date
	3,806,829	04/23/74	Duston, et al.	331	94.5	04/13/71
	4,016,504	04/05/77	Klauminzer	331	94.5	04/12/76
	4,309,671	01/05/82	Malyon	331	94.5S	12/18/80
	4,319,843	03/16/82	Gornall	356	346	02/25/80
	4,331,937	05/25/82	Brown, et al.	372	74	03/20/80
	4,348,647	09/07/82	Nighan, et al.	372	74	06/05/80
	4,393,505	07/12/83	Fahlen	372	57	11/03/81
	4,404,366	09/13/83	Boguslaski, et al.	536	18.1	07/16/81
	4,435,808	03/06/84	Javan	372	11	01/22/81
	4,468,773	08/28/84	Seaton	372	32	05/29/81
	4,513,422	04/23/85	Buholz	372	29	06/14/83
	4,558,952	12/17/85	Kulesh, et al.	356	349	02/18/83
	4,592,043	05/27/86	Williams	370	3	04/24/83
	4,611,270	09/09/86	Klauminzer, et al.	364	183	09/16/83
	4,616,908	10/14/86	King	350	576	07/19/84
	4,691,322	09/01/87	Nozue, et al.	372	82	01/22/86
	4,823,354	04/18/89	Znotins, et al.	372	57	12/15/87
	4,829,536	05/09/89	Kajiyama, et al.	372	57	06/09/87
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	4,911,778	03/27/90	Barnoach	156	466	10/23/87
	4,914,662	04/03/90	Nakatani, et al.	372	32	09/26/88
	4,926,428	05/15/90	Kajiyama, et al.	372	20	08/31/87
	4,975,919	12/04/90	Amada, et al.	372	33	03/18/88
	4,977,573	12/11/90	Bittenson, et al.	372	81	03/09/89
	5,025,445	06/18/91	Anderson, et al.	372	20	11/22/89
	5,081,635	06/14/92	Wakabayashi, et al.	372	57	08/25/98
	5,095,492	03/10/92	Sandstrom	372	102	07/17/90
	5,142,543	08/25/92	Wakabayashi, et al.	372	32	01/27/89
	5,144,632	09/01/92	Thonn	372	33	03/15/91
	5,150,370	09/22/92	Furuya, et al.	372	106	12/12/90
	5,198,872	03/30/93	Wakabayashi, et al.	356	352	05/18/90
	5,218,421	06/08/93	Wakabayashi, et al.	356	352	02/15/91
	5,221,823	06/22/93	Usui	219	121.78	01/17/92

Examiner

Date Considered

Examiner: Initial if citation considered, whether or not citation is in conference with MPEP 609; Draw line through citation if not conformance and not considered. Include a copy of this form with the next communication to applicant.

Form PTO 1449 (Rev. 2-32)		U.S. Department of Commerce Patent and Trademark Office		Atty. Docket No. LMPY-12910		Serial No. 09/903,425	
<div style="border: 1px solid black; border-radius: 50%; padding: 10px; display: inline-block; transform: rotate(-45deg);"> OIPE FEB 03 2003 PATENT & TRADEMARK OFFICE </div>				Information Disclosure Statement by Applicant		Applicant: Hans-Stephan Albrecht, et al.	
(Use several sheets if necessary)				Filed: July 10, 2001		Group: 2881	
U.S. Patent Documents							
		Document No.	Date	Name	Class	Subclass	Filing Date
		5,225,884	07/06/93	Stark, et al.	356	73	06/05/91
		5,226,050	07/06/93	Burghardt	372	20	01/25/91
		5,307,364	04/26/94	Turner	372	60	05/24/93
		5,337,330	08/09/94	Larson	372	86	10/09/92
		5,373,515	12/13/94	Wakabayashi, et al.	372	20	06/21/91
		5,396,514	03/07/95	Voss	372	57	03/01/93
		5,404,366	04/04/98	Wakabayashi et al.	372	29	02/14/94
		5,420,877	05/30/95	Sandstrom	372	34	07/16/93
		5,450,207	09/12/95	Fomenkov	356	416	07/16/93
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		5,559,584	09/24/96	Miyaji, et al.	355	73	01/30/95
		5,559,816	09/24/96	Basting, et al.	372	27	05/30/95
		5,596,596	01/21/97	Wakabayashi, et al.	372	102	12/15/95
		5,642,374	06/24/97	Wakabayashi, et al.	372	57	04/10/95
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		5,663,973	09/02/97	Stamm, et al.	372	20	06/10/96
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		5,748,346	05/05/98	David, et al.	359	15	05/12/97
		5,761,236	06/02/98	Kleinschmidt, et al.	372	100	07/18/96
		5,763,855	06/09/98	Shioji	219	121.84	06/02/95
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		5,771,094	06/23/98	Carter, et al.	356	326	01/29/97
		5,802,094	09/01/98	Wakabayashi, et al.	372	57	10/10/96
		5,811,753	09/22/98	Weick, et al.	219	121.78	06/19/96
		5,818,865	10/06/98	Watson, et al.	372	86	05/16/97
		5,835,520	11/10/98	Das, et al.	372	57	04/23/97
		5,852,627	12/22/98	Ershov	372	108	09/10/97
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		5,867,514	02/02/99	Anderson	372	38	01/09/97
Examiner <i>Jee</i>					Date Considered <i>06/28/03</i>		
Examiner: Initial if citation considered, whether or not citation is in conference with MPEP 609; Draw line through citation if not conformance and not considered. Include a copy of this form with the next communication to applicant.							

Form PTO 1449
(Rev. 2-32)U.S. Department of Commerce
Patent and Trademark OfficeAtty. Docket No.
LMPY-12910Serial No.
09/903,425

Information Disclosure Statement by Applicant

Applicant:

Hans-Stephan Albrecht, et al.

(Use several sheets if necessary)

Filed: July 10, 2001 Group: 2881

U.S. Patent Documents

Init.	Document No.	Date	Name	Class	Subclass	Filing Date
	5,898,725	04/27/99	Fomenkov, et al.	372	102	01/21/97
	5,901,163	05/04/99	Ershov	372	20	12/08/97
	5,914,974	06/22/99	Partlo, et al.	372	38	02/21/97
	5,917,849	06/29/99	Ershov	372	102	09/10/97
	5,936,988	08/10/99	Partlo, et al.	372	38	07/18/98
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	5,946,337	08/31/99	Govorkov, et al.	372	92	04/29/98
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	5,970,082	10/19/99	Ershov	372	102	07/01/97
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	5,978,394	11/02/99	Newman, et al.	372	32	10/02/98
	5,978,406	11/02/99	Rokni, et al.	372	58	01/30/98
	5,978,409	11/02/99	Das, et al.	372	100	09/28/98
	5,982,795	11/09/99	Rothweil, et al.	372	38	12/22/97
	5,982,800	11/09/99	Ishihara, et al.	H01S	3/22	10/10/97
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	6,028,872	02/22/00	Partlo, et al.	372	38	12/15/98
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	6,081,542	06/27/00	Scaggs	372	70	06/12/98
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	6,151,346	11/21/00	Partlo, et al.	372	38	08/09/99
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	6,160,831	12/12/00	Kleinschmidt, et al.	372	57	03/17/99

Examiner

Date Considered

6/28/03

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				Filed: July 10, 2001 Group: 2881			
U.S. Patent Documents							
Init.	Document No.	Date	Name	Class	Subclass	Filing Date	
	6,160,832	12/12/00	Kleinschmidt, et al.	372	57	10/12/99	
	6,163,559	12/19/00	Watson	372	102	06/22/98	
	6,198,761	03/06/01	von Bergmann, et al.	372	86	09/03/99	
	6,212,214	04/03/01	Vogler, et al.	372	59	08/23/99	
	6,219,368	04/17/01	Govorkov	372	59	06/30/99	
	6,226,307	05/01/01	Desor, et al.	372	37	11/02/99	
	6,240,110	07/31/01	Leinhos, et al.	372	57	10/05/98	
	6,243,163	06/05/01	Wakabayashi, et al.	356	326	09/17/99	
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	6,285,701	09/04/01	Albrecht, et al.	372	57	08/06/98	
HU	2001/0013933A1	08/16/01	Smith, et al.	356	454	12/14/00	
Foreign Documents							
							Translation
Init.	Document No.	Date	Country	Class	Subclass	Yes	No
HU	P 40 29 687 A1	09/19/90	Germany	H01S	3/082		X
	DE 41 14 407 A1	11/05/92	Germany	G01J	9/2		X
	DE 42 25 781 A1	08/04/92	Germany	H01S	3/08		X
	EP 0 570 243 A1	05/14/93	EP	H01s	3/139	X	
	EP 0 454 399 B1	09/20/95	EPO	H01S	3/137	X	
	WO 96/07224	03/07/96	PCT	H01S	3/13		
	EP 0 855 811 A2	07/29/98	EPO	H04B	10/145	X	
	EP 0 875 743 A1	11/04/98	EPO	G01J	9/02	X	
	EP 0 867 989 B1	09/01/99	EPO	H01S	3/1055	X	
	DE 298 22 090 U1	02/03/99	Germany	H01S	3/08		X
	DE 298 22 082 U1	02/03/99	Germany	H01S	3/08		X
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	EP 0 472 727 B1	11/29/90	EPO	H01S	3/1055		
	EP 1 063 503 A1	12/27/00	EPO	G01J	9/02		
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	WO 01/46658A1	06/01/01	PCT(English Abstract)	G01J	3/18		
HU	JP 2-631554	04/25/97	Japan	H01S	3/1055	X	
Examiner				Date Considered			
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Other Documents (Including Author, Title, Date, Pertinent Pages, etc.)			
		Smara, S., "Wavelength Shifts in Hg ¹⁹⁸ as a Function of Temperature," <u>Journal of Research of the National Bureau of Standards - A. Physics and Chemistry</u> , Vol. 65A, No. 6, November-December 1961, pp. 473-474.	
		J. Caplan, "Temperature and Pressure Effects on Pressure-Scanned Etalons and Gratings," <u>Applied Optics</u> , Vol. 14, No. 7, July 1975, pp. 1585-1591	
		Masakatsu Okada et al., "Electronic Tuning of Dye Lasers by an Electro-optic Birefringent Fabry-Perot Etalon," <u>Optics Communications</u> , Vol. 14, No. 1, pp. 4-7, 1975.	
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		H. H. Barrett, et al., "Retroreflective arrays as approximate phase conjugators," <u>Opt. Lett.</u> 4, Vol. 4, No. 6, 1979, pp. 190-192.	
		R.A. Keller et al., "Opto-galvanic Spectroscopy in a Hollow Cathode Discharge," <u>J. Opt. Soc. Am.</u> , Vol. 69, No. 5, pp. 738-742, May 1979.	
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		N. Tan-No, et al., "Dispersion-free amplification and oscillation in phase-conjugate four-wave mixing in an atomic vapor doublet," <u>IEEE J. Quantum Electronics</u> , 16, 1980, pp. 147-153.	
		W. Demtröder, <u>Laser Spectroscopy</u> , published by Springer, Berlin 1981, Chapter 4: Spectroscopic Instrumentation, pp. 99-221.	
		M.D. Levenson, et al., "Projection photolithography by wave-front conjugation," <u>J. Opt. Soc. Am.</u> , Vol. 71, No. 6, June 1981, pp. 737-743.	
		T.R. Hicks, "Tunable Fabry-Perot Filters," <u>Opt. Eng.</u> , Vol. 20, No. 6 (1981) pp. 806-514.	
		Norman J. Dovichi, et al., "Use of the Optogalvanic Effect and the Uranium Atlas for Wavelength Calibration of Pulsed Lasers," <u>Applied Optics</u> , Vol. 21, No. 8, pp. 1468-1473, April 12, 1982.	
		D.L. Jordan, et al., "Experimental Measurements of Non-Gaussian Scattering by a Fractal Diffuser," <u>Applied Physics B</u> , Vol. 31, 1983, pp. 179-186.	
		P. Camus, "Atomic Spectroscopy with Optogalvanic Detection," <u>Journal De Physique</u> , (Paris) 11C7, pp. C7-87-106, November 1983.	
		R. Martinez-Herrero, et al., "Transmitted Amplitude by a Fabry-Perot Interferometer with Random Surface Defects," <u>Applied Optics</u> , Vol. 24, No. 3, February 1, 1985, pp. 315-316.	
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Applicant:
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